

Description

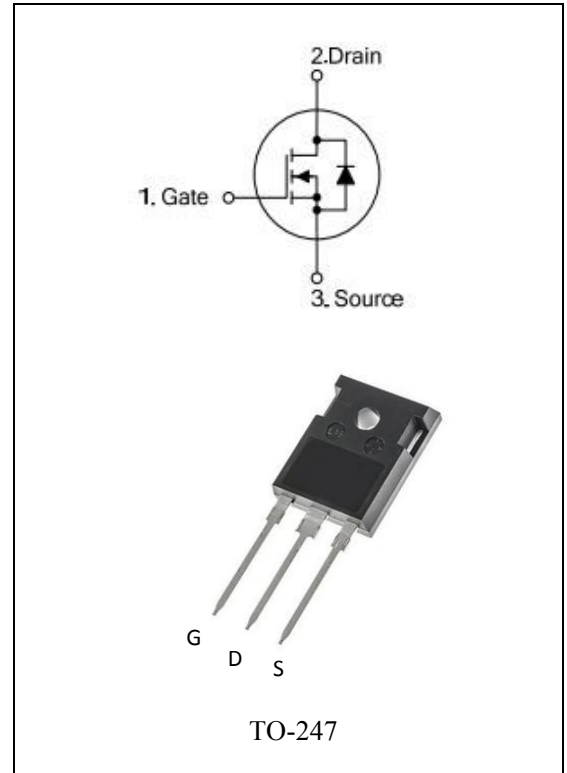
MLS60R150W, the silicon N-channel Enhanced MOSFETs, is obtained by advanced Super Junction technology which reduce the conduction loss, improve switching performance. The transistor is suitable device for SMPS, high speed switching and general purpose applications.

KEY CHARACTERISTICS

- ① $V_{DS}=600V$, $R_{dson}<150m\Omega$ @ $V_{GS}=10V$, $I_D=26A$ (Typ:126m Ω)
- ① Fast Switching
- ② 100% avalanche tested
- ③ Improved dv/dt capability
- ④ RoHS product

APPLICATIONS

- ① High frequency switching mode power supply



ORDERING INFORMATION

Ordering Codes	Package	Product Code	Packing
MLS60R150-W	TO-247	M60R150W	Tube

ABSOLUTE RATINGS at $T_c = 25^\circ C$, unless otherwise specified

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	600	V
I_D	Continuous Drain Current	26	A
	Continuous Drain Current $T_c = 100^\circ C$	16	A
I_{DM}	Pulsed Drain Current(Note1)	75.9	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy(Note2)	600	mJ
dv/dt	Peak Diode Recovery dv/dt(Note3)	15	V/ns
P_D	Power Dissipation TO-220 TO-262 TO-263 TO-3PN	220	W
	Derating Factor above $25^\circ C$	1.75	W/ $^\circ C$
P_D	Power Dissipation TO-220F	42	W
	Derating Factor above $25^\circ C$	0.33	W/ $^\circ C$



T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150	°C
T_L	Maximum Temperature for Soldering	300	°C

Thermal characteristics

Symbol	Parameter	RATINGS	Units
$R_{\theta JC}$	Junction-to-Case	0.57	°C/W
$R_{\theta JA}$	Junction-to-Ambient	62.5	°C/W

Electrical Characteristics at $T_C = 25^\circ\text{C}$, unless otherwise specified

OFF Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	600	--	--	V
$\Delta BV_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu A$, Reference 25°C	--	0.63	--	V/°C
I_{DSS}	Drain to Source Leakage Current	$V_{DS}=600V, V_{GS}=0V,$ $T_j = 25^\circ\text{C}$	--	--	1	μA
		$V_{DS}=480V, V_{GS}=0V,$ $T_j = 125^\circ\text{C}$	--	--	100	μA
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+30V$	--	--	100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-30V$	--	--	-100	nA
ON Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On- Resistance	$V_{GS}=10V, I_D=9A(\text{Note4})$	--	0.126	0.15	Ω
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS},$ $I_D = 250\mu A(\text{Note4})$	2.5	--	4.5	V
Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
R_g	Gate resistance	$f = 1.0\text{MHz}$	--	3.2	--	Ω
C_{iss}	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1.0\text{MHz}$	--	1860	--	PF
C_{oss}	Output Capacitance		--	1060	--	
C_{rss}	Reverse Transfer Capacitance		--	56	--	

Switching Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D = 8.5A$ $V_{DD} = 300V$ $V_{GS} = 10V$ $R_G = 5\Omega$	--	100.4	--	ns
t_r	Rise Time		--	61	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	220.6	--	
t_f	Fall Time		--	54.8	--	
Q_g	Total Gate Charge	$I_D = 11A$ $V_{DD} = 400V$ $V_{GS} = 10V$	--	43	--	nC
Q_{gs}	Gate to Source Charge		--	10	--	
Q_{gd}	Gate to Drain ("Miller") Charge		--	16	--	
Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)	$T_C = 25^\circ C$	--	--	26	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	75.9	A
V_{SD}	Diode Forward Voltage	$I_S = 11A, V_{GS} = 0V$ (Note4)	--	--	1.2	V
T_{rr}	Reverse Recovery Time	$I_S = 11A,$ $T_j = 25^\circ C$ $dI_F/dt = 100A/us$	--	267.6	--	ns
Q_{rr}	Reverse Recovery Charge		--	4069	--	nC
I_{rrm}	Reverse Recovery Current		--	26.8	--	A

Note1: Pulse width limited by maximum junction temperature

Note2: $L=20mH, V_{DS}=50V, Start T_J=25^\circ C$

Note3: $I_{SD} = 11A, d_i/d_t \leq 100A/us, V_{DD} \leq B_{VDS}, Start T_J = 25^\circ C$

Note4: Pulse width $t_p \leq 300\mu s, \delta \leq 2\%$

Characteristics Curves

Figure 1a Safe Operating Area (No FullPAK)

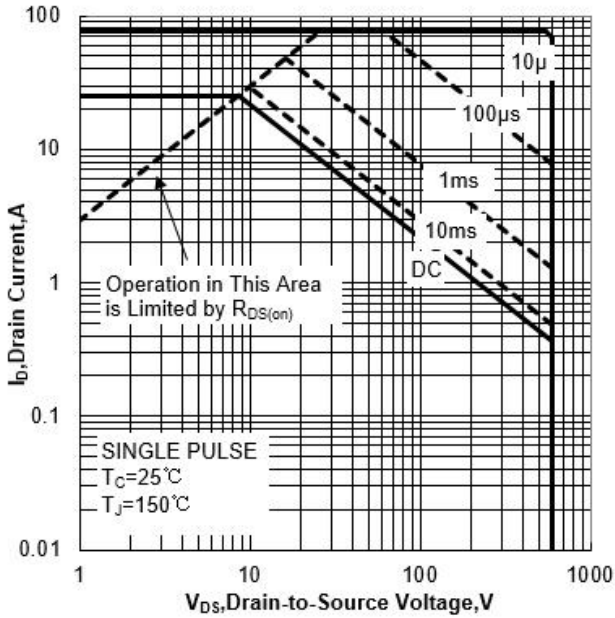


Figure 1b Safe Operating Area (FullPAK)

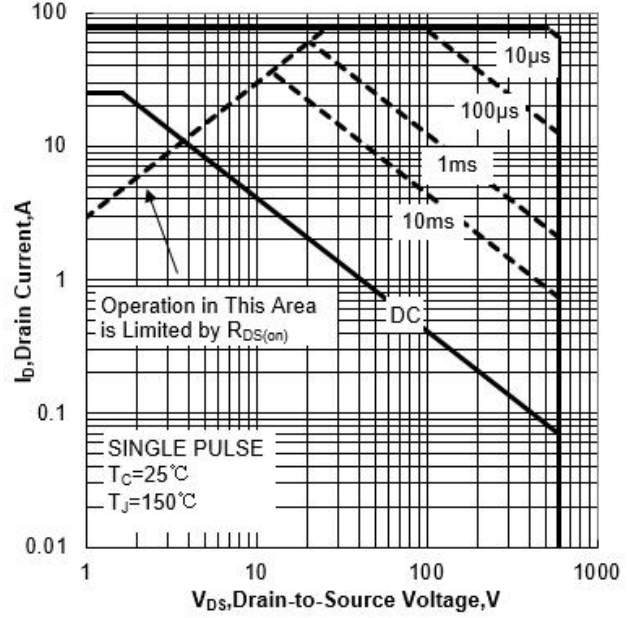


Figure 2a Power Dissipation (No FullPAK)

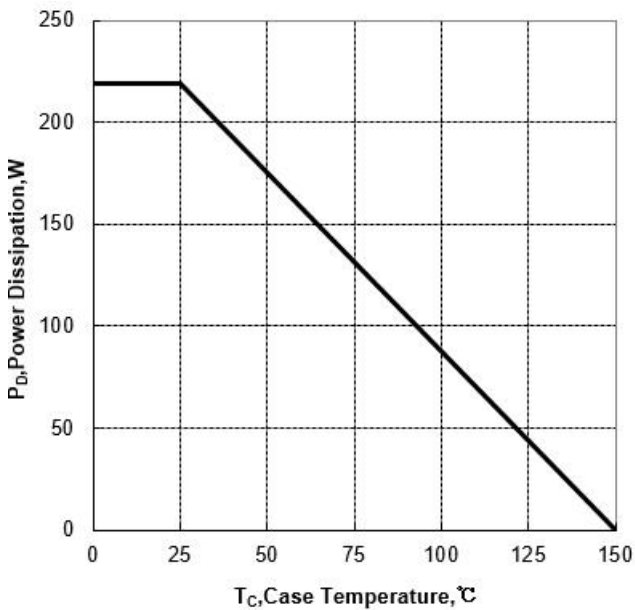


Figure 2b Power Dissipation (FullPAK)

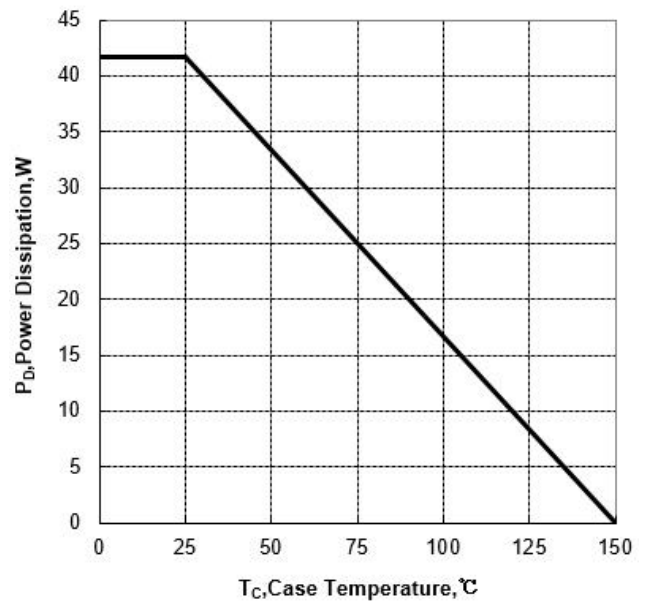


Figure 3a Max Thermal Impedance (No FullPAK)

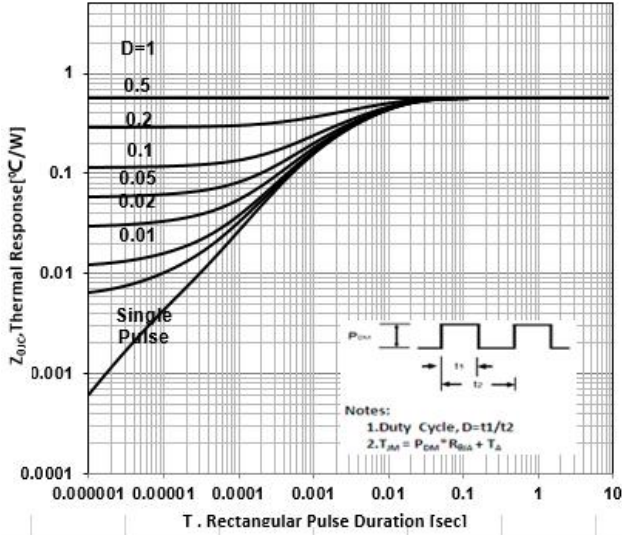


Figure 3b Max Thermal Impedance (FullPAK)

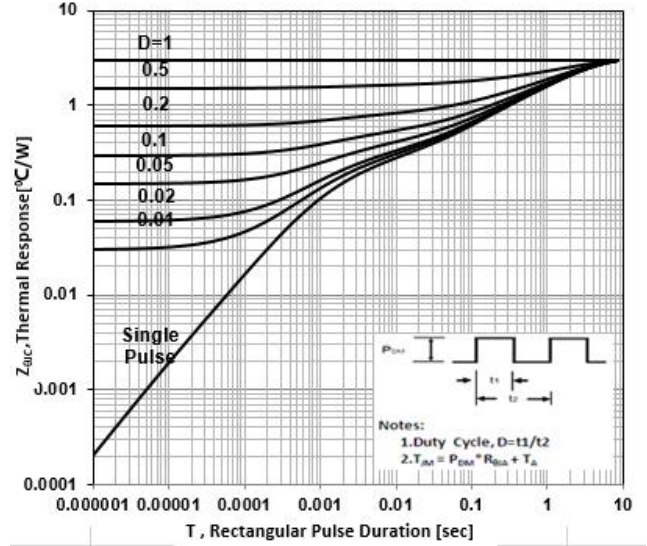


Figure 4 Typical Output Characteristics

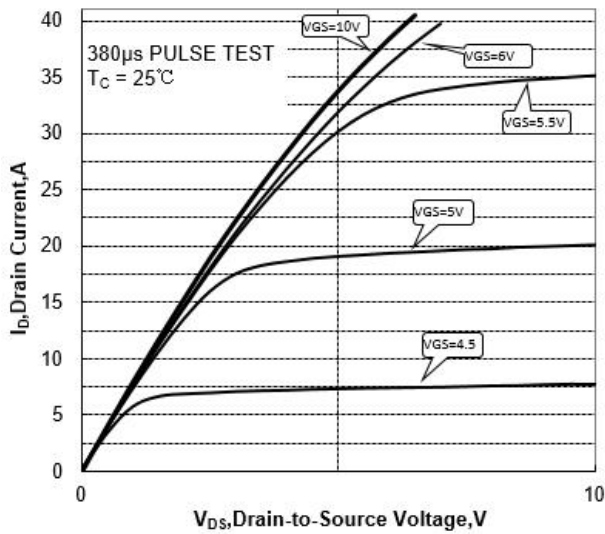


Figure 5 Typical Transfer Characteristics

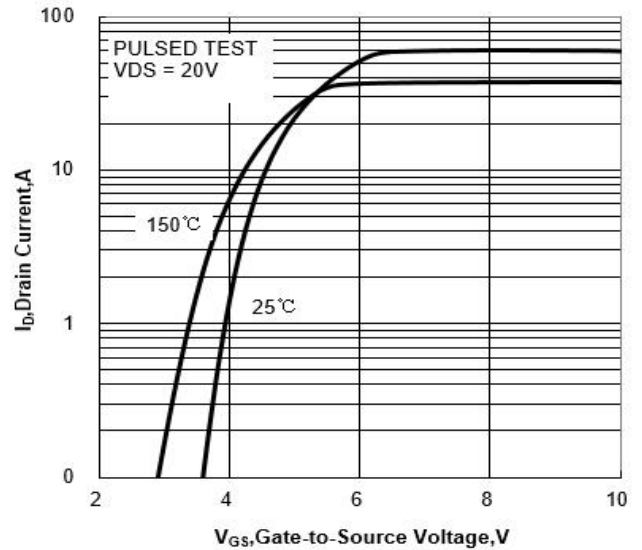


Figure 6 Typical Drain to Source ON Resistance vs Drain Current

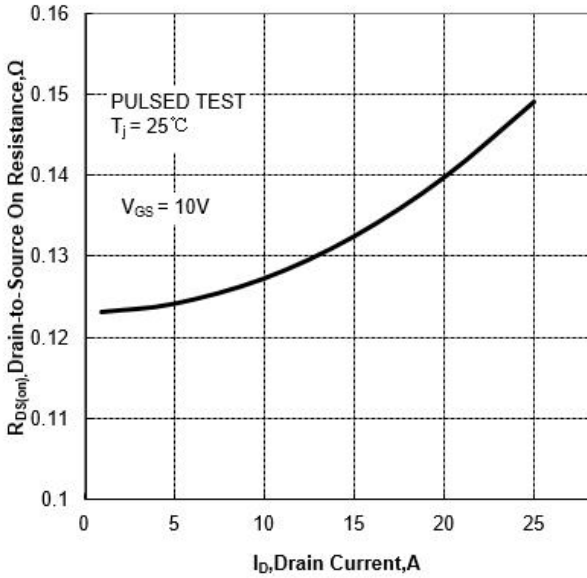


Figure 7 Typical Drain to Source on Resistance vs Junction Temperature

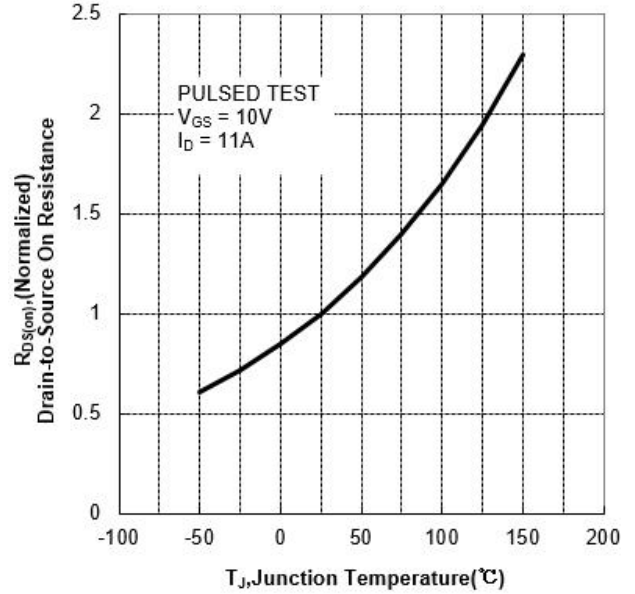


Figure 8 Typical Threshold Voltage vs Junction Temperature

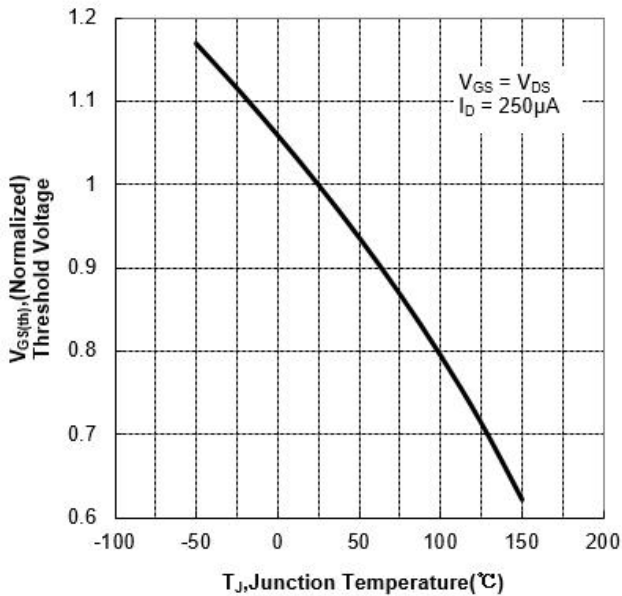


Figure 9 Typical Breakdown Voltage vs Junction Temperature

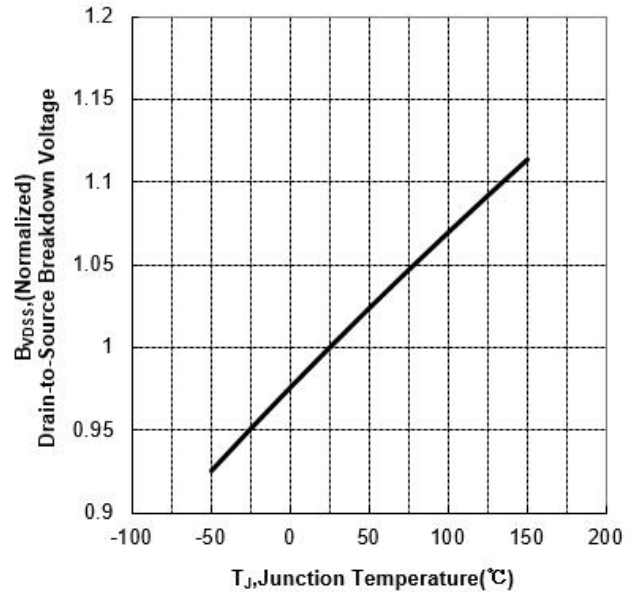


Figure 10 Typical Capacitance vs Drain to Source Voltage

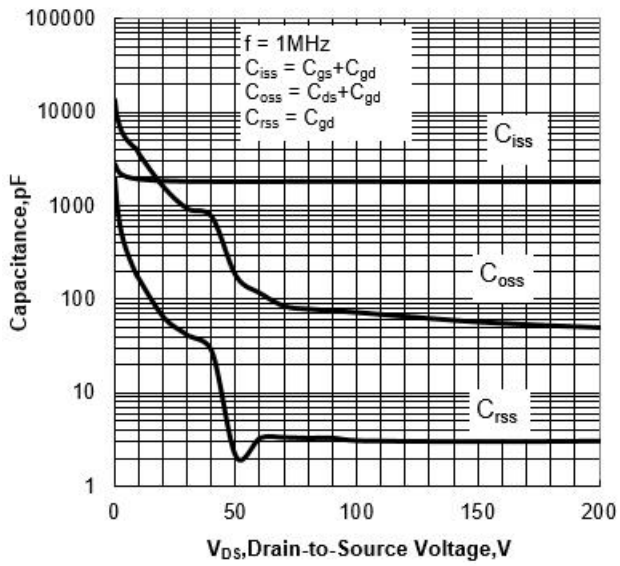
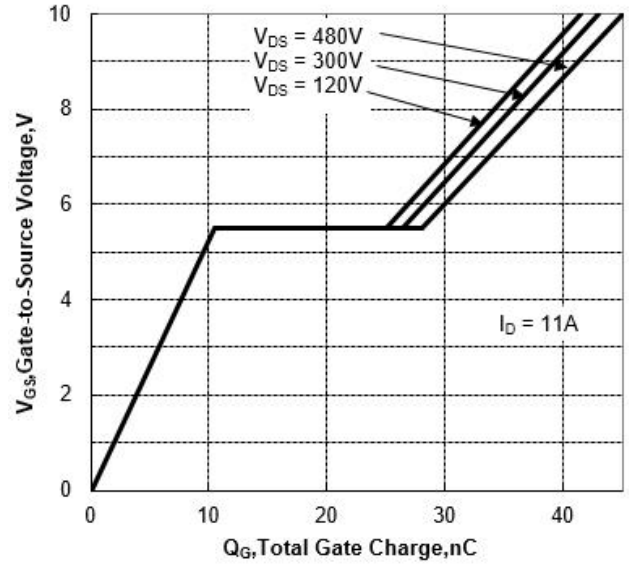


Figure 11 Typical Gate Charge vs Gate to Source Voltage



Test Circuit and Waveform

Figure 12 Gate Charge Test Circuit

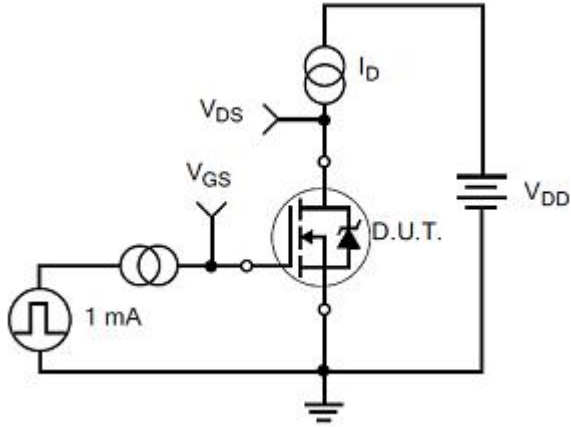


Figure 13 Gate Charge Waveforms

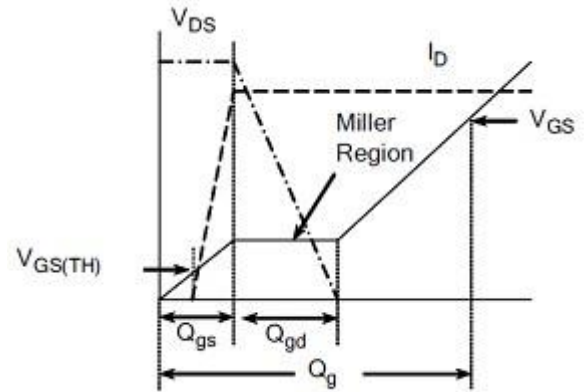


Figure 14 Resistive Switching Test Circuit

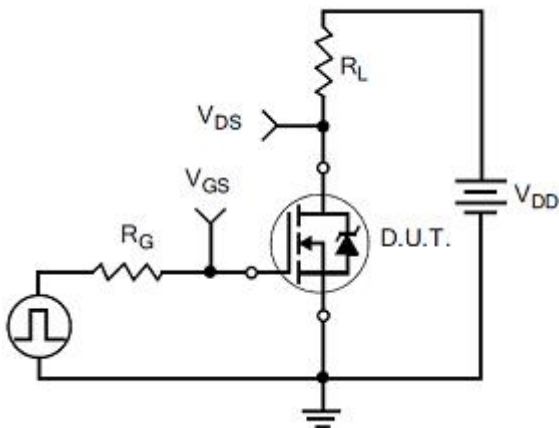


Figure 15 Resistive Switching Waveforms

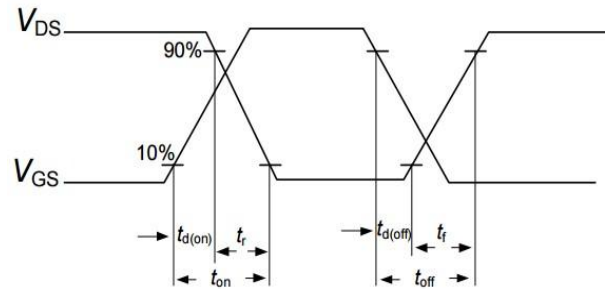


Figure 16 Diode Reverse Recovery Test Circuit

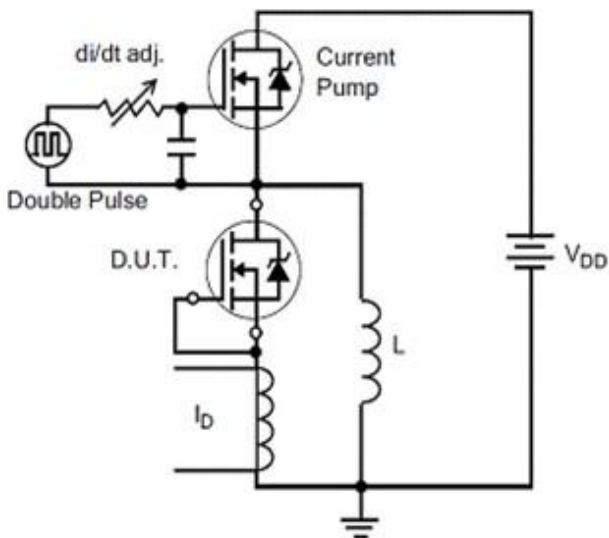


Figure 17 Diode Reverse Recovery Waveform

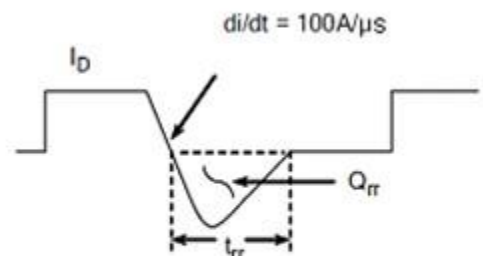


Figure 18 Unclamped Inductive Switching Test Circuit

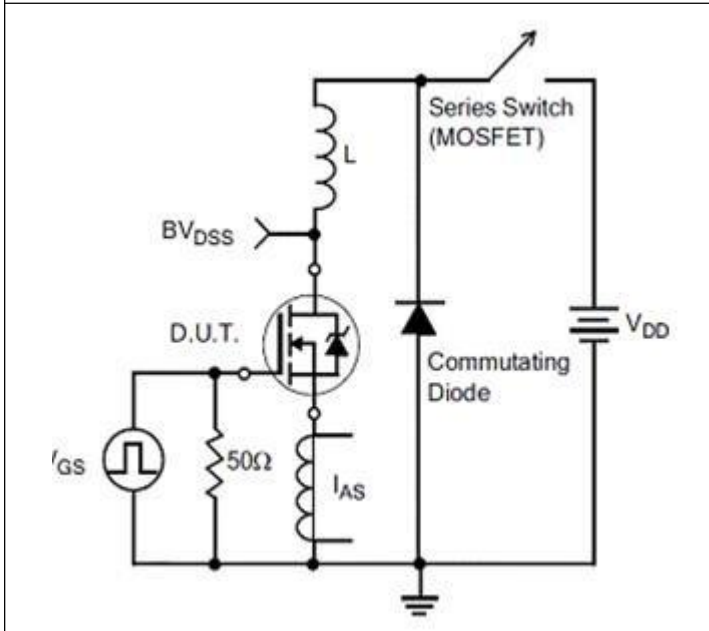
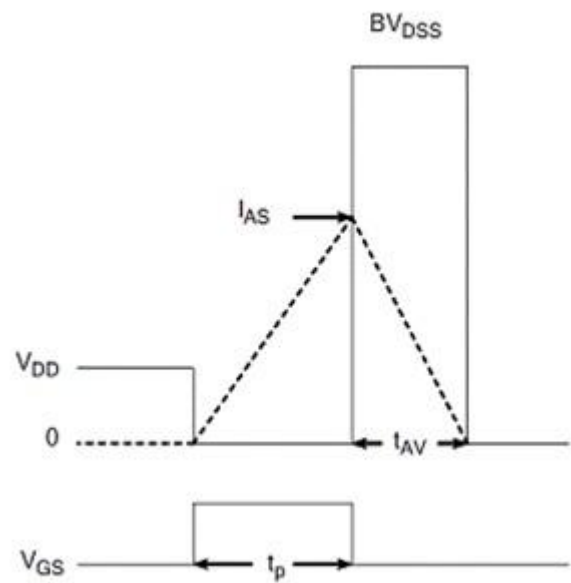
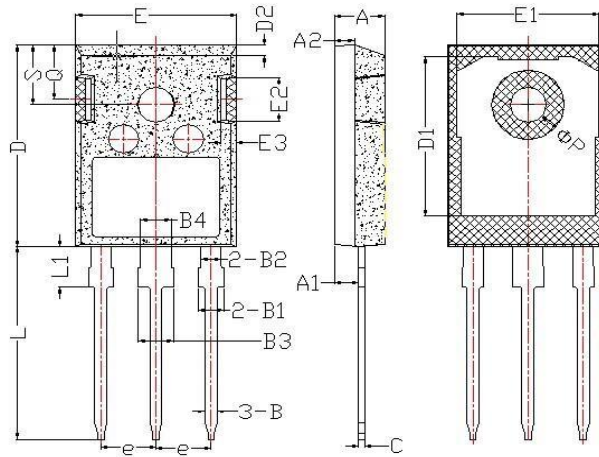


Figure 19 Unclamped Inductive Switching Waveform



Package Description



Items	Values(mm)	
	MIN	MAX
A	4.6	5.2
A1	2.2	2.6
B	0.9	1.4
B1	1.75	2.35
B2	1.75	2.15
B3	2.8	3.35
B4	2.8	3.15
C	0.5	0.7
D	20.60	21.30
D1	16	18
E	15.5	16.10
E1	13	14.7
E2	3.80	5.3
E3	0.8	2.60
e	5.2	5.7
L	19	20.5
L1	3.9	4.6
ΦP	2.5	3.70
Q	5.2	6.00
S	5.8	6.6

TO-247 Package



NOTE:

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shenzhen Minos reserves the right to make changes in this specification sheet and is subject to change without prior notice.

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